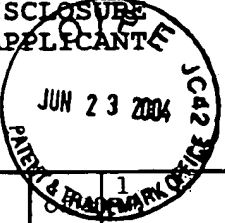


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U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		Application Number	10/802,139
		Filing Date	March 17, 2004.
		First Named Inventor	Kazuhiko OMOTE
		Group Art Unit	2853
		Examiner Name	Not Yet Assigned <i>K. Suchecki</i>
Sheet	1	Attorney Docket Number	04176/LH


U.S. PATENT DOCUMENTS

Exam. Inits [*]	Cite No ¹	Document Number	Kind Code ²	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion
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FOREIGN PATENT DOCUMENTS

Exam. Inits [*]	Cite No ¹	Offc ³	Document Number ⁴	Kind Code ⁵	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion	T ⁶
<i>40</i>	A	JP	11-304731	A	RIGAKU DENKI KK	11-05-1999		X [*]
<div style="position: relative; width: 100%; height: 100%;"> <div style="position: absolute; top: 0; left: 0; right: 0; bottom: 0; border-left: 2px solid black; border-right: 2px solid black;"></div> </div>								

*English Language Abstract only

Examiner Signature		Date Considered	06/09/05
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^{*} EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Place a check here if English translation is attached.

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Substitute for Form 1449A/PTO SEP 16 2004 INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	10/802,139
				Filing Date	March 17, 2004
				First Named Inventor	Kazuhiko OMOTE
				Group Art Unit	2882
				Examiner Name	K Suchecki
Sheet	1	of	3	Attorney Docket Number	04176/LH

U.S. PATENT DOCUMENTS

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AO		6,282,263	B1	ARNDT et al	08-28-2001	
						

FOREIGN PATENT DOCUMENTS

Exam Inits ¹	Cite No ¹	Offc ³	Document Number ⁴	Kind Code ⁵	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion	T ⁶
								

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Substitute for Form 1449A/PTO				Application Number		10/802,139	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Filing Date		March 17, 2004	
				First Named Inventor		Kazuhiko OMOTE	
				Group Art Unit		2882	
				Examiner Name		K. Suchacki	
Sheet	2	of	3	Attorney Docket Number		04176/LH	
OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS							
Examiner Initials ¹	Cite No. ¹	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published					T ²
NO		X. X. JIANG et al: "STUDY OF STRAIN AND COMPOSITION OF THE SELF-ORGANIZED GE DOTS BY GRAZING INCIDENT X-RAY DIFFRACTION", NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH SECTION - A: ACCELERATORS, SPECTROMETERS, DETECTORS AND ASSOCIATED EQUIPMENT, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL, Vol. 467-468, 21 July 2001 (2001-07-21), pages 362-365, XP004297870, ISSN: 0168-9002. * Chapter "2. Experimental" on pages 363-364. - *reference 12*.					
NO		X. JIANG et al: "STATUS OF THE 4W1C BEAMLINE AND THE DIFFUSE SCATTERING EXPERIMENTAL STATION AT THE BEIJING SYNCHROTRON RADIATION FACILITY", NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH SECTION - B: BEAM INTERACTIONS WITH MATERIALS AND ATOMS, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL, Vol. 129, No. 4, 1 September 1997 (1997-09-01), pages 543-547, XP004089038, ISSN: 0168-583X. *Chapter "3. X-Ray Diffuse Scattering Station" - *Figure 2*.					
NO		M. S. GOORSKY et al: "GRAZING INCIDENCE IN-PLANE DIFFRACTION MEASUREMENT OF IN-PLANE MOSAIC WITH MICROFOCUS X-RAY TUBES", CRYSTAL RESEARCH AND TECHNOLOGY, 2002, WILEY-VCH VERLAG BERLIN GmbH, Germany, "Online!", Vol. 37, No. 7, pages 645-653, XP002289273, ISSN: 0232-1300, Retrieved from the Internet: <URL:http://www.crystalresearch.com/crt/ab37/645_a.pdf>, retrieved on 2004-07-21!, *Chapter "Experimental Requirements"*.					
NO		"BEDE D1 WITH MICROSCOPE", UCLA MATERIALS SCIENCE & ENGINEERING, "Online! 12 November 2002 (2002-11-12), XP002289274, Retrieved from the Internet: <URL:http://www.seas.ucla.edu/igoorsky/xray/Dlmicro..html>, retrieved on 2004-07-21!, *the whole document*.					
NO		LICAI JIANG et al: "APPLICATION OF MULTILAYER OPTICS TO X-RAY DIFFRACTION SYSTEMS", THE RIGAKU JOURNAL, "Online!", Vol. 18, No. 2, 2001, pages 13-22, XP002289275, Retrieved from the Internet: ,URL:http://www.rigakumsc.com/journal/Vol18.2.2001/Jiang.pdf>, retrieved on 2004-07-21!, *page 19, last paragraph - page 20, paragraph 1, Figure 13.*					
NO		K. OMOTE: "DIRECT OBSERVATION OF IN-PLANE TEXTURE IN COBALT RECORDING MEDIA BY MEANS OF A LABORATORY-SCALE X-RAY DIFFRACTOMETER", X-RAY SPECTROMETRY, NOV.-DEC. 1999, WILEY, U.K., Vol. 28, No. 6, pages 440-445, XP009034007, ISSN: 0049-8246 - *page 442*.					
NO		B. VERMAN: "MICROFOCUSING SOURCE AND MULTILAYER OPTICS BASED X-RAY DIFFRACTION SYSTEMS", THE RIGAKU JOURNAL, "Online!", Vol. 19, No. 1, 2002, pages 4-13, XP002289276, Retrieved from the Internet: <URL:http://www.riguksc.com/journal/Vol19.1.2002/verman.pdf>, retrieved on 2004-07-21, *page 4*, *page 8, right-hand column, line 5 - line 19; table 4*.					
NO		A. K. MALHOTRA et al: "IN SITU/EX SITU X-RAY ANALYSIS SYSTEM FOR THIN SPUTTERED FILMS", SURF COAT TECHNOL.; SURFACE & COATINGS TECHNOLOGY, Nov. 10, 1998, Elsevier Science S.A., Lausanne, Switzerland, Vol. 110, No. 1-2, 10 November 1998 (1998-11-10), pages 105-110, XP002288818 - *page 106*.					
NO		"ULTIMA III", RIGAKU, "Online!", 4 February 2004 (2004-02-04), XP002289277, Retrieved from the Internet: <URL:http://www.rigakumsc.com/xrd/ultima.html>, retrieved on 2002-07-21, *the whole document*.					
Examiner Signature					Date Considered		06/09/05

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Sheet	3	of	3	Attorney Docket Number		04176/LH	
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Examiner Initials ¹	Cite No. ¹	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published					T ²
UK		Y. HIRAI et al: "THE DESIGN AND PERFORMANCE OF BEAMLINE BL16XU AT SPRING-8", NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH, SECTION - A: ACCELERATORS, SPECTROMETERS, DETECTORS AND ASSOCIATED EQUIPMENT, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL, Vol. 251, No. 2-3, 2 April 2004 (2004-04-01), pages 538-548, XP004498331, ISSN: 0168-9002, *Chapter "2.5..2. X-ray diffractometer system", on pages 545, 546* - "reference 22*".					
Examiner Signature					Date Considered		06/09/05

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